

L Number	Hits	Search Text	DB	Time stamp
1	3183190	@ad<20010322	USPAT	2004/09/02 17:00
2	551702	semiconductor or IC or LSI or VLSI or ASIC or chip or wafer	USPAT	2004/09/02 17:01
3	3510	metrological or metrology	USPAT	2004/09/02 17:01
4	280	field-to-field or (field adj to adj field)	USPAT	2004/09/02 17:02
5	1361276	analys\$ or data or measurement or error	USPAT	2004/09/02 17:03
7	3752	residual-error or (residual adj error) or (residu\$ adj (error or data or analysis or measurement))	USPAT	2004/09/02 17:05
6	2	(semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and (metrological or metrology) and (field-to-field or (field adj to adj field)) and (analys\$ or data or measurement or error)	USPAT	2004/09/02 17:13
9	2	(semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and ((field-to-field or (field adj to adj field)) same (analys\$ or data or measurement or error)) and (residual-error or (residual adj error) or (residu\$ adj (error or data or analysis or measurement)))	USPAT	2004/09/02 17:15
8	2	(semiconductor or IC or LSI or VLSI or ASIC or chip or wafer) and (field-to-field or (field adj to adj field)) and (analys\$ or data or measurement or error) and (residual-error or (residual adj error) or (residu\$ adj (error or data or analysis or measurement)))	USPAT	2004/09/02 17:44
10	453	703/6.ccls.	USPAT	2004/09/02 17:44
11	823	430/22.ccls.	USPAT	2004/09/02 17:44
12	182	382/147.ccls.	USPAT	2004/09/02 17:44
13	1457	703/6.ccls. or 430/22.ccls. or 382/147.ccls.	USPAT	2004/09/02 17:44
15	1189	(703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<20010322	USPAT	2004/09/02 17:45
16	684	((703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<20010322) and (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer)	USPAT	2004/09/02 17:45
17	2	((((703/6.ccls. or 430/22.ccls. or 382/147.ccls.) and @ad<20010322) and (semiconductor or IC or LSI or VLSI or ASIC or chip or wafer)) and (field-to-field or (field adj to adj field))	USPAT	2004/09/02 17:45

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9/2/04